

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L2	0	(364/578).CCLS.	USPAT	OR	OFF	2005/02/14 13:02
L3	0	(364/489).CCLS.	USPAT	OR	OFF	2005/02/14 13:03
L4	2450	((714/25) or (714/27) or (714/32) or (714/724) or (714/737) or (714/741) or (714/797)).CCLS.	USPAT	OR	OFF	2005/02/14 13:09
L5	79	4 and (test adj coverage)	USPAT	OR	ON	2005/02/14 13:10
L6	1	5 and events and hits	USPAT	OR	OFF	2005/02/14 13:14
L7	2451	((716/4) or (716/5) or (703/14) or (703/13)).CCLS.	USPAT	OR	OFF	2005/02/14 13:15
L8	65	7 and (test adj coverage)	USPAT	OR	ON	2005/02/14 13:15
L9	15	8 and event and hit	USPAT	OR	ON	2005/02/14 13:15

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	2451	((716/4) or (716/5) or (703/14) or (703/13)).CCLS.	USPAT	OR	OFF	2005/02/14 13:33
L2	65	1 and (test adj coverage)	USPAT	OR	ON	2005/02/14 13:33
L3	15	2 and event and hit	USPAT	OR	ON	2005/02/14 13:34
L4	3	("20020147969"   "5752002"   "6463582").PN. OR ("6775810").URPN.	US-PGPUB; USPAT; USOCR	OR	OFF	2005/02/14 13:44

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S1	17	coverage adj analysis adj tool	USPAT	OR	OFF	2005/02/14 09:49
S2	18	coverage adj analysis adj tool	USPAT	OR	ON	2005/02/14 09:49

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Software Reliability Engineering, 2001. ISSRE 2001. Proceedings. 12th International Symposium on , 27-30 Nov. 2001

Pages:276 - 286

[\[Abstract\]](#)   [\[PDF Full-Text \(2124 KB\)\]](#)   **IEEE CNF**

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### 1 Ordered sequence testing criteria for concurrent programs and the support tool

*Itoh, E.; Kawaguchi, Y.; Furukawa, Z.; Ushijima, I.;*

Software Engineering Conference, 1994. Proceedings., 1994 First Asia-Pacific , 7-9 Dec. 1994

Pages:236 - 245

[\[Abstract\]](#)   [\[PDF Full-Text \(612 KB\)\]](#)   IEEE CNF

### 2 A method for structural testing of Ada concurrent programs using the Event Interactions Graph

*Katayama, T.; Furukawa, Z.; Ushijima, K.;*

Software Engineering Conference, 1996. Proceedings. 1996 Asia-Pacific , 4-7 Dec. 1996

Pages:355 - 364

[\[Abstract\]](#)   [\[PDF Full-Text \(700 KB\)\]](#)   IEEE CNF

### 3 A tool for testing hypermedia systems

*Leung, H.K.N.;*

EUROMICRO Conference, 1999. Proceedings. 25th , Volume: 2 , 8-10 Sept. 1999

Pages:202 - 209 vol.2

[\[Abstract\]](#)   [\[PDF Full-Text \(128 KB\)\]](#)   IEEE CNF

### 4 Considering browser interaction in Web application testing

*Di Lucca, G.A.; Di Penta, M.;*

Web Site Evolution, 2003. Theme: Architecture. Proceedings. Fifth IEEE International Workshop on , 22 Sept. 2003

Pages:74 - 81

[\[Abstract\]](#)   [\[PDF Full-Text \(329 KB\)\]](#)   IEEE CNF

### 5 A quantitative measure of integrity error

*Farrell, J.L.;*

Position Location and Navigation Symposium, 1994., IEEE , 11-15 April 1994

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**1 Software reliability growth with test coverage**

*Malaiya, Y.K.; Li, M.N.; Bieman, J.M.; Karcich, R.;*

Reliability, IEEE Transactions on , Volume: 51 , Issue: 4 , Dec. 2002

Pages:420 - 426

[\[Abstract\]](#)   [\[PDF Full-Text \(415 KB\)\]](#)   IEEE JNL

**2 Single-ended SRAM with high test coverage and short test time**

*Chua-Chin Wang; Chi-Feng Wu; Rain-Ted Hwang; Chia-Hsiung Kao;*

Solid-State Circuits, IEEE Journal of , Volume: 35 , Issue: 1 , Jan. 2000

Pages:114 - 118

[\[Abstract\]](#)   [\[PDF Full-Text \(120 KB\)\]](#)   IEEE JNL

**3 Cryptographic verification of test coverage claims**

*Devanbu, P.T.; Stubblebine, S.G.;*

Software Engineering, IEEE Transactions on , Volume: 26 , Issue: 2 , Feb. 2000

Pages:178 - 192

[\[Abstract\]](#)   [\[PDF Full-Text \(228 KB\)\]](#)   IEEE JNL

**4 Using simulation for assessing the real impact of test-coverage on defect-coverage**

*Briand, L.C.; Pfahl, D.;*

Reliability, IEEE Transactions on , Volume: 49 , Issue: 1 , March 2000

Pages:60 - 70

[\[Abstract\]](#)   [\[PDF Full-Text \(272 KB\)\]](#)   IEEE JNL

**5 Achieving software quality with testing coverage measures**

*Horgan, J.R.; London, S.; Lyu, M.R.;*

Computer , Volume: 27 , Issue: 9 , Sept. 1994

Pages:60 - 69

[\[Abstract\]](#)   [\[PDF Full-Text \(788 KB\)\]](#)   IEEE JNL

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**1 Capping off the undergraduate degree in technical communication - some options**

*Davis, M.T.; Grice, R.A.; Williams, T.R.;*  
 Professional Communication Conference, 2004. IPCC2004. Proceedings.  
 International , Sept. 29-Oct. 2, 2004  
 Pages:314 - 320

[\[Abstract\]](#)   [\[PDF Full-Text \(755KB\)\]](#)   IEEE CNF

**2 Sustaining technical communication programs: a conversation**

*Davis, M.T.;*  
 Professional Communication Conference, 2004. IPCC2004. Proceedings.  
 International , Sept. 29-Oct. 2, 2004  
 Pages:47 - 48

[\[Abstract\]](#)   [\[PDF Full-Text \(427KB\)\]](#)   IEEE CNF

**3 Technical communication degrees for the 21<sup>st</sup> century**

*Davis, M.T.;*  
 Professional Communication Conference, 2000. Proceedings of 2000 Joint IEEE  
 International and 18th Annual Conference on Computer Documentation  
 (IPCC/SIGDOC 2000) , 24-27 Sept. 2000  
 Pages:69 - 74

[\[Abstract\]](#)   [\[PDF Full-Text \(388KB\)\]](#)   IEEE CNF

**4 Technical communication and distance learning: natural partners**

*Davis, M.T.;*  
 Professional Communication Conference, 1997. IPCC '97 Proceedings. 'Crossroads  
 in Communication'. , 1997 IEEE International , 22-25 Oct. 1997  
 Pages:37 - 43

[\[Abstract\]](#)   [\[PDF Full-Text \(412KB\)\]](#)   IEEE CNF

**5 A MEMS electro spray nozzle for mass spectroscopy**

*Desai, A.; Yu-Chong Tai; Davis, M.T.; Lee, T.D.;*  
 Solid State Sensors and Actuators, 1997. TRANSDUCERS '97 Chicago., 1997  
 International Conference on , Volume: 2 , 16-19 June 1997  
 Pages:927 - 930 vol.2

[\[Abstract\]](#)   [\[PDF Full-Text \(600KB\)\]](#)   IEEE CNF

## **6 Delivering education in the next millennium**

*Davis, M.T.;*

Professional Communication Conference, 1996. IPCC '96 Proceedings.  
'Communication on the Fast Track', International , 18-20 Sept. 1996  
Pages:34 - 36

[\[Abstract\]](#) [\[PDF Full-Text \(136KB\)\]](#) IEEE CNF

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## **7 Shaping the profession: Leading academic programs in technical communication**

*Davis, M.T.; Gurak, L.; Ramey, J.; Krull, R.; Williams, J.; Steehouder, M.;*

Professional Communication Conference, 2003. IPCC 2003. Proceedings. IEEE  
International , Sept. 21-24, 2003  
Pages:102 - 103

[\[Abstract\]](#) [\[PDF Full-Text \(208KB\)\]](#) IEEE CNF

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## **8 Educating reflective practitioners**

*Davis, M.T.; Grady, H.M.; Hayhoe, G.F.;*

Professional Communication Conference, 2002. IPCC 2002. Proceedings. IEEE  
International , 17-20 Sept. 2002  
Pages:157 - 165

[\[Abstract\]](#) [\[PDF Full-Text \(749KB\)\]](#) IEEE CNF

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## **9 Who are we? Ethnography of technical communicators**

*Davis, M.T.;*

Professional Communication Conference, 1999. IPCC 99. Communication Jazz:  
Improvising the New International Communication Culture. Proceedings. 1999 IEEE  
International , 7-10 Sept. 1999  
Pages:135 - 136

[\[Abstract\]](#) [\[PDF Full-Text \(64KB\)\]](#) IEEE CNF

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## **10 Integrating technical communication into engineering education: a case study**

*Grady, H.M.; Davis, M.T.;*

Professional Communication Conference, 1998. IPCC 98. Proceedings. 1998 IEEE  
International , Volume: 2 , 23-25 Sept. 1998  
Pages:265 - 270 vol.2

[\[Abstract\]](#) [\[PDF Full-Text \(472KB\)\]](#) IEEE CNF

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## **11 Seeking ABET accreditation for technical communication programs**

*Haselkorn, M.; Davis, M.T.; Goodman, M.B.; Nolen, B.E.;*

Professional Communication Conference, 1998. IPCC 98. Proceedings. 1998 IEEE  
International , Volume: 2 , 23-25 Sept. 1998  
Pages:195 - 196 vol.2

[\[Abstract\]](#) [\[PDF Full-Text \(104KB\)\]](#) IEEE CNF

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## **12 Educating the technical communication professional of tomorrow**

*Davis, M.T.; Grady, H.M.; Leonard, D.C.;*

Professional Communication Conference, 1995. IPCC '95 Proceedings. 'Smooth  
sailing to the Future', IEEE International , 27-29 Sept. 1995  
Pages:98 - 99

[\[Abstract\]](#) [\[PDF Full-Text \(200KB\)\]](#) IEEE CNF

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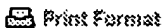
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Components, Packaging, and Manufacturing Technology, Part B: Advanced Packaging, IEEE Transactions on [see also Components, Hybrids, and Manufacturing Technology, IEEE Transactions on] , Volume: 18 , Issue: 3 , Aug. 1995

Pages:406 - 415

[\[Abstract\]](#)[\[PDF Full-Text \(964 KB\)\]](#)**IEEE JNL**